

A METHOD FOR LOCATING I_{DDQ} DEFECTS USING MULTIPLE CONTROLLED COLLAPSE CHIP CONNECTIONS CURRENT MEASUREMENT ON AN AUTOMATIC TESTER

Abstract of the Disclosure

A method for improving the signal-to-noise ratio in an I_{DDQ} defect test is disclosed. An integrated circuit is divided into a plurality of areas and each area is provided with and bounded by terminals. An I_{DDQ} defect is activated to generate I_{DDQ} defect current within the integrated circuit. An amount of I_{DDQ} defect current generated within each area is measured at the terminals provided thereto. Based on the I_{DDQ} current measurement on each area, an I_{DDQ} current map is created. By analyzing the I_{DDQ} current map, the presence and location of the defect is determined. Based on the determination, the I_{DDQ} defect is isolated.